CLAIMS

What is claimed is:

1 1. A memory struc	cture comprising
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- a plurality of substrates stacked one on another;
- a plurality of connectors connecting said substrates to one another; and 3 at least one memory chip package mounted on each of said substrates, ACSTRITT LIPES wherein said connectors have a size sufficient to form a gap between said substrates,

wherein said gap is larger than a height of said memory chip package.

- The memory structure in claim 1, wherein said memory chip package comprises a 2. pre-tested memory chip package that is tested for defects before being mounted on said substrates.
- The memory structure in claim 1, wherein said memory chip package and said substrates 1
- 2 include identical electrical connections.
- 1 The memory structure in claim 1, wherein each of said substrates has a plurality of said
- 2 memory chip packages mounted thereon.

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- 1 5. The memory structure in claim 1, wherein said connectors comprises solder balls.
- 1 6. The memory structure in claim 1, further comprising a thermal connection between a top
- of said memory chip package and a bottom of an adjacent substrate, such that said thermal
- 3 connection fills said gap.
 - 7. The memory structure in claim 1, wherein said memory chip package comprises a chip having an array of memory elements mounted within a package.
 - 8. A memory structure comprising:
 - a plurality of substrates stacked one on another;
 - a plurality of connectors connecting said substrates to one another; and
 - at least one memory chip package mounted on each of said substrates,
 - wherein said connectors have a size sufficient to form a gap between said substrates,
 - wherein said gap is larger than a height of said memory chip package, and
- 7 wherein each memory chip package includes only a single memory chip.
- 1 9. The memory structure in claim 8, wherein said memory chip package comprises a
- 2 pre-tested memory chip package that is tested for defects before being mounted on said
- 3 substrates.

- 1 10. The memory structure in claim 8, wherein said memory chip package and said substrates
- 2 include identical electrical connections.
- 1 11. The memory structure in claim 8, wherein each of said substrates has a plurality of said
- 2 memory chip packages mounted thereon.
- 1 12. The memory structure in claim 8, wherein said connectors comprise solder balls.
 - 13. The memory structure in claim 8, further comprising a thermal connection between a top of said memory chip package and a bottom of an adjacent substrate, such that said thermal connection fills said gap and said memory chip package includes a single memory chip.
 - 14. The memory structure in claim 8, wherein said memory chip package comprises a chip having an array of memory elements mounted within a package.
- 1 15. A method of manufacturing a memory structure comprising:
- 2 forming a plurality of chip packages on a memory chip;
- attaching at least one first memory chip package to a first substrate;
- 4 attaching a second substrate to said first substrate using connectors; and
- 5 attaching at least one second memory chip package to said second substrate,
- 6 wherein said connectors have a size sufficient to form a gap between said first substrate
- and said second substrate, wherein said gap is larger than a height of said first memory

- 1 16. The method in claim 15, further comprising testing said first memory chip package and
- 2 said second memory chip package before said attaching of said first memory chip package and
- 3 said attaching of said second memory chip package.
 - 17. The method in claim 15, wherein said first memory chip package and said second memory chip package and said first substrate and said second substrate include identical electrical connections.
 - 18. The method in claim 15, wherein each of said first substrate and said second substrate has a plurality of said memory chip packages mounted thereon.
 - 19. The method in claim 15, wherein said connectors comprise solder balls.
- 1 20. The method in claim 15, further comprising forming a thermal connection between a top
- 2 of said first memory chip package and a bottom of said second substrate, such that said thermal
- 3 connection fills said gap.